

MS1454

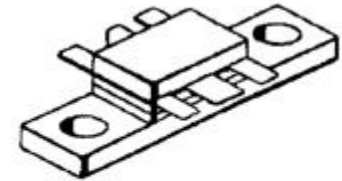
RF AND MICROWAVE TRANSISTORS 806-960 MHZ CELLULAR BASE STATIONS

Features

- Gold Metallization
- Diffused Emitter Ballasting
- Internal Input Matching
- Designed for Linear Operation
- High Saturated Power Capability
- Common Emitter Configuration
- P_{OUT} 30 W MIN
- Gain 7.5 dB
- Efficiency 55% (Typ)
- 20:1 VSWR
- Overdrive Survivability 5 dB

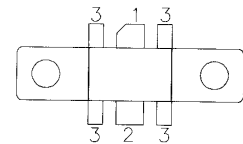
DESCRIPTION:

The MS1454 gold/metallized epitaxial silicon NPN planar transistor uses diffused emitter ballast resistors for high linearity class AB operation in cellular base station applications.



.230 6LFL (M142)
epoxy sealed

PIN CONNECTION



1. Collector 3. Base
2. Emitter

ABSOLUTE MAXIMUM RATINGS ($T_{case} = 25^{\circ}C$)

Symbol	Parameter	Value	Unit
V_{CBO}	Collector-Base Voltage	48	V
V_{CEO}	Collector-Emitter Voltage	25	V
V_{EBO}	Emitter-Base Voltage	3.5	V
P_{DISS}	Total Power Dissipation	88	W
I_C	Collector Current	7.5	A
T_j	Junction Temperature	+200	$^{\circ}C$
T_{stg}	Storage Temperature	-65 to +150	$^{\circ}C$

THERMAL DATA

$R_{TH(j-c)}$	Junction-Case Thermal Resistance	2	$^{\circ}C/W$
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ELECTRICAL SPECIFICATIONS (T_{case} = 25°C)
STATIC

Symbol	Test Conditions	Value			Unit
		Min.	Typ.	Max.	
BV_{CES}	I_C = 100 mA	48	55	---	V
BV_{EBO}	I_E = 10 mA	3.5	5	---	V
BV_{CEO}	I_C = 40 mA	25	28	---	V
BV_{CER}	I_E = 40 mA R_{BE} = 100 Ω	30	40	---	V
I_{CBO}	V_{CE} = 24 V	---	---	---	mA
h_{FE}	V_{CE} = 20 V I_C = 2 A	15	40	100	---

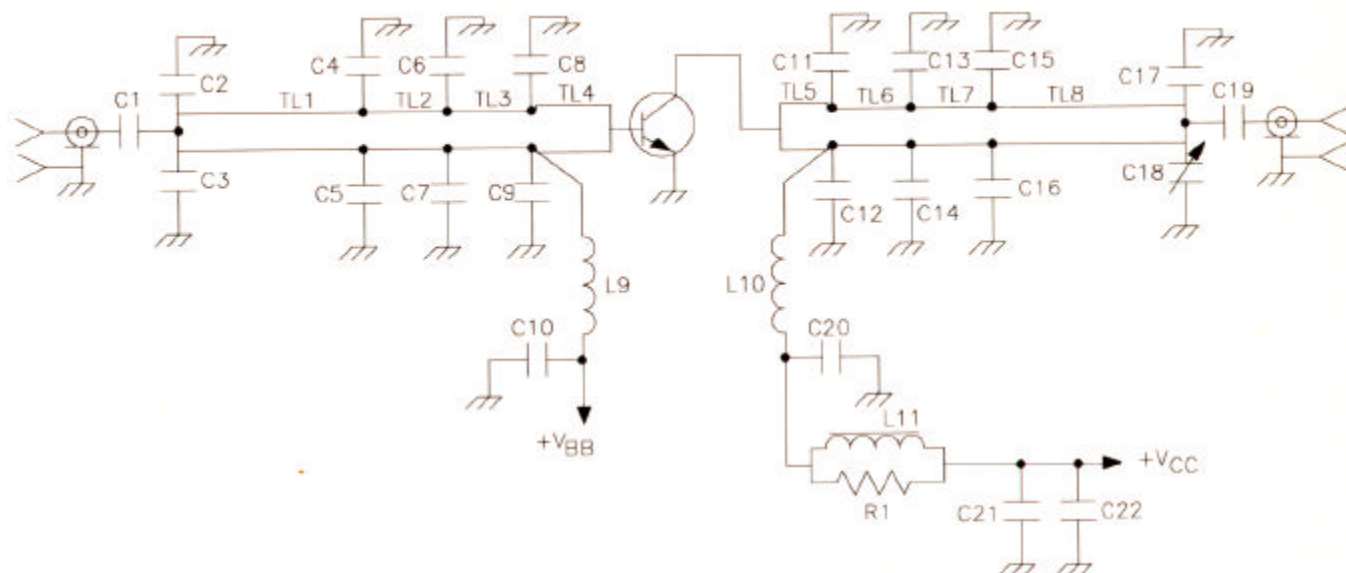
DYNAMIC

Symbol	Test Conditions	Value			Unit
		Min.	Typ.	Max.	
P_{OUT}	f = 860 MHz I_{CQ} = 60 mA V_{CE} = 25 V	30	---	---	W
η_C	f = 860 MHz I_{CQ} = 60 mA V_{CE} = 25 V	---	55	---	%
G_P	f = 860 MHz I_{CQ} = 60 mA V_{CE} = 25 V	7.5	9	---	DB
C_{OB}	V_{CB} = 25 V f₀ = 1 MHz	---	42	---	pF
IMD₃	P_{OUT} = 30 W PEP f₁ = 860.0 MHz f₂ = 860.1 MHz	---	-35	---	dBc
VSWR₁	VSWR = 20:1 V_{CE} = 25 V VSWR = 10:1 V_{CE} = 25 V ± 20%	NO DEGRADATION IN OUTPUT DEVICE			Typ.
VSWR₂	VSWR = 5:1 V_{CE} = 25 V ± 20% P_{IN} = P_{IN} (norm) + 3 dB	NO DEGRADATION IN OUTPUT DEVICE			Typ.
OVD	P_{IN}(norm) = +5dB V_{CE} = 25 V P_{IN}(norm) = +5dB V_{CE} = 25 V ± 20%	NO DEGRADATION IN OUTPUT DEVICE			Typ.

IMPEDANCE DATA

Freq.	$Z_{IN} (\Omega)$	$Z_{CL} (\Omega)$
800 MHz	$4.3 + j 5.8$	$3.5 + j 0.2$
830 MHz	$3.2 + j 6.1$	$3.5 + j 0.1$
860 MHz	$3.5 + j 7.1$	$2.9 - j 0.2$
900 MHz	$5.3 + j 6.4$	$2.0 - j 0.6$
915 MHz	$6.1 + j 6.3$	$3.2 - j 0.7$
930 MHz	$9.4 + j 6.3$	$3.2 - j 1.1$
945 MHz	$6.6 + j 3.0$	$3.3 - j 1.2$
960 MHz	$5.9 + j 1.0$	$3.4 - j 1.5$

TEST CIRCUIT

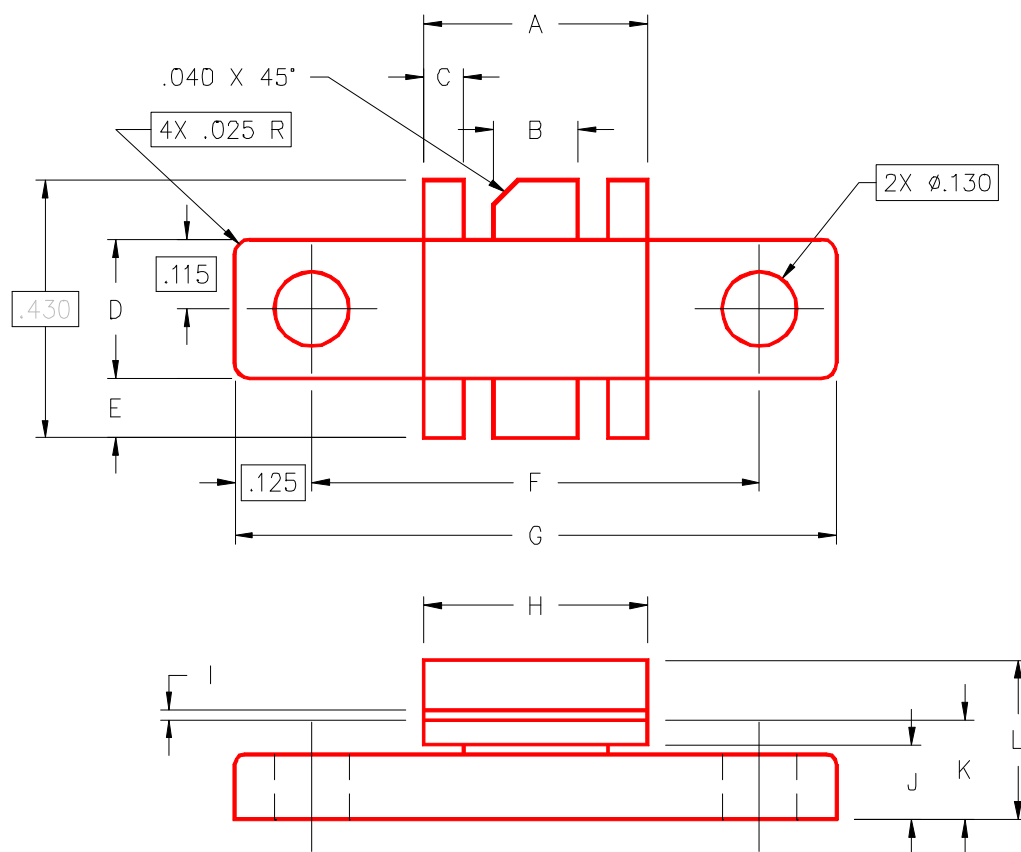


C1, C19 : 33pF ATC 100B Chip Capacitor
 C2, C15 : 3.6pF ATC 100B Chip Capacitor
 C3 : 4.5pF ATC 100B Chip Capacitor
 C4, C16 : 5.0pF ATC 100B Chip Capacitor
 C5 : 2.9pF ATC 100B Chip Capacitor
 C6, C7 : 1.8pF ATC 100B Chip Capacitor
 C8, C9 : 6.2pF ATC 100B Chip Capacitor
 C10, C22 : 300pF ATC 100B Chip Capacitor
 C11, C12

C18 : .5 - 6.0pF Gigatrim Adjustable Capacitor
 C20 : 10pF ATC 100B Chip Capacitor
 C21 : 10μF (50V) Electrolytic Capacitor
 L9 : 4 Turns (tight) I.D. 120mil ENAM Cu 20 AWG
 L10 : 4 Turns (tight) I.D. 158mil ENAM Cu 18 AWG
 L11 : 1.5 Turns VK-200 Ferrite H.F. Choke
 TL1, TL8 : 964 x 85.69 mils (50Ω/36.84")
 TL2, TL3 : 352 x 85.69 mils (50Ω/13.46")
 TL4 : 222 x 109.03 mils (42.6Ω/8.56")
 TL5 : 149 x 109.03 mils (42.6Ω/5.74")
 TL6 : 334 x 85.69 mils (50Ω/12.75")

PACKAGE MECHANICAL DATA

PACKAGE STYLE M142



	MINIMUM INCHES/MM	MAXIMUM INCHES/MM		MINIMUM INCHES/MM	MAXIMUM INCHES/MM
A	.355/9,02	.365/9,27	I	.004/0,10	.006/0,15
B	.115/2,92	.125/3,18	J	.120/3,05	.130/3,30
C	.075/1,91	.085/2,16	K	.160/4,06	.180/4,57
D	.225/5,72	.235/5,97	L	.230/5,84	.260/6,60
E	.090/2,29	.110/2,79			
F	.720/18,29	.730/18,54			
G	.970/24,64	.980/24,89			
H	.355/9,02	.365/9,27			